Specification MOS/CV1391/Issue 3	SECURITY
Dated:- December 1957. To be read in conjunction with K1001 and BS.448	Specification Yalve Unclassified Unclassified

Indicates a change

TYPE OF DEFLECTION: - Elec	node R ay Tub e strostatic sui ner symmetrica		MARKING See K1001/4 BASE BS.448. B 12 D			
•	metrical volt trestatic	ages.				
cond	rnally coated uctive coatin		CONNECTIONS			
SCREEN:- BB3			<u>Pin</u>	Electrode		
RATING Heater Voltage Heater Current Max. Final Anode Voltage X plate sensitivity Y plate sensitivity TYPICAL OPERATING CONDITY		1.0 5 620 Va3 1160 Va3	1 2 3 4 5 6 7 8 9 10 11 12	g k h h ai a2 Internal coating y2 x2 a3 x1 y1		
Final Anode Voltage Second Anode Voltage First Anode Voltage Beam Current	(EF) (V) (EF) (UA)	3 475 2 30	DIMENSIONS See drawing, Page 4 PACKAGING See K1005			

NOTE:-

A:- The focussing system shall be of the three electrode type .

B:- The tube must be adequately free from Microphony and Deflection Defocus. These tests will be covered by Type Approval.

To be performed in addition to those applicable in K1001

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8				Limits	
Clause	Test Conditions Tests		Min.	Max.	Test e d
à	See K1001/5A.13	Capacitances (pf) 1. Each X plate to all other electrodes. 2. Each Y plate to all other electrodes. 3. Grid to all other electrodes.	-	25 25 25	2 %(5)
		4. Each X plate to each Y plate.	***	3	·

FOR ALL TESTS GIVEN BELOW Vh = 4.0V

ь	·	Ih	(A)	0.66	1.2	100%
С	Cathode 100 volts positive to heater. Cathode 50 volts negative to heater.	Heater Cathode Current 1. Current 2. Current	(uA)	-	100 50	100% 100%

FOR ALL TESTS GIVEN BELOW EXCEPT CLAUSE (K) Vai = 2 kV. Va3 = 3 kV

	FUR ALL TESTS GIVEN BEI	ON EACE	FI CENUOE (K) VO	- 2 AT,	10)	, v.	
đ	With a raster scan of convenient size adjust Va2 for optimum focus and Vg for a light intensity of 0.7 "orthochromatic candela." See K1001.5A.9.	2. U	Vg. Value to be no seful screen area. K direction Y direction	ted (V) (mm) (mm)	5 ±60 ±52		100% 100%
e	Vg as in test "d". With an elliptical scan of length 100 mm. in the X and Y directions successively adjust Va2 for optimum focus. The minor axis of the ellipse should not exceed 5 mm.	1. L	ine width	(mm) (V)	325	0.9 625	100% 100%
ſ	Va2 adjusted for optimum focus and Vg for cut-off.	77 77 10 3. Wi 11 11 11	Vg. ncrease in negative alue of Vg compare alue noted in test initial. ithin the range of oltage from cut-of hat obtained in clane beam current sh ncrease continuous	d with (V) grid f to suse d1 all	5	35	100% 100% 100%

TESTS (Contd)

			Limits		No.
	Test Conditions	Tests	Min.	Max.	Tested
g	See K1001/5A.3.2. (a) Vg-80V. (b) Alternative method Resistor 10 meg.	Grid Insulation (a) Leakage Current (uA) (b) Increase in voltmeter reading. (%)	-	8 100	100%
h		Deflection Sensitivities 1. X plate (mm/V) 2. Y plate (mm/V)	Va3	700 Va3 1300 Va3	10%(10)
3	See K1001/5A.11.1.	Deviation of spot from centre of screen (mm)	ı	10	100%
k	With Va3 at 5 kV See K1001/5A.14.	Over Voltage Test			100%
1		Orientation of deflection Axes 1. Orientation of X axis of deflection relative to OO' on dwg. 2. Angle between X and Y axes of deflection	80° 85°	100° 95°	100% 100%
m	A screen area of at least 100 mm, x 100 mm, to be scanned with asymmetrical deflection.	Trapezoidal Distortions 1. Angles between adjacent sides 2. Angles between opposite sides	85°	950 185 0	10%(10)
m	See K1001/11.5.	Vibration.			T. A.

DRAWING NOTE

The neck diameter may be less than 68 mm. if the manufacturer provides two rings of an approved material of outside diameter within the specified tolerances.

